WAN Tester III

- Tests asynchronous, synchronous, T-1, fractional T-1, E-1 and fractional E-1, T-3 and E-3 facilities and equipment
- V.35, RS232, RS422/RS530, X.21, HSSI, dual T-1, dual E-1, dual T-3 and dual E-3 interfaces
- Data rates from 50 bps to 50 Mbps
- Displays G.821 performance measurements
- Front panel Color LCD Display, TELNET, VT100 and Command Line Interface control
- Includes a built-in LAN Interface for TELNET and TFTP
- AC or battery power

The Telinc WAN Tester III is a sophisticated bit error rate tester in a compact, hand held package. It can test a wide variety of communications facilities and equipment including T-1, fractional T-1, E-1, fractional E-1, T-3 and E-3 modems, multiplexers, CSU/DSUs, T-1 CSUs, DTUs, NTUs and TIUs. It is supplied with user changeable nickel metal hydride batteries and a built-in charger.

Dual T-1 and E-1 Testing

In the T-1 and E-1 modes, the Tester displays bit errors, transmit and receive frequency, test seconds, bit error rate and G.821 performance measurements. A variety of test patterns can be inserted in all or selected DS0s/TimeSlots, continuous or non-contiguous, making the Tester ideal for fractional T-1 or E-1 testing. Because it contains two T-1/E-1framers, it can measure bit and frame slips as well as monitor and listen to both the TX and RX DS0s and TimeSlots simultaneously. It can also perform Drop/Insert (D/I) testing a single DS0 or TimeSlot without interfereing with the remaining ones

Dual T-3 and E-3 Testing

The WAN Tester III can test T-3 and E-3 networks and CSUs. It performs G.821 measurements and displays bit errors, bit error rate, frequency and more. With the dual T-3/E-3 TX and RX framers and codecs, it can monitor both sides of the line so it can listen to voice on a DS0 or Timeslot on a channelized T-3/E-3.

Asynchronous and Synchronous Testing

In the async and sync test mode, the Tester generates test data in a choice of patterns and formats. The user can choose from twenty-eight async and seventy-five sync test speeds. In the async mode, it displays characters received, character errors and errored seconds. In the sync mode, it displays bit errors, bit error rate, TX frequency, RX frequency, CTS delay, G.821 measurements and more.

Reports

The WAN Tester III can generate and store reports useful for line turnovers, troubleshooting in the lab or diagnosing a communication line issue.

Easy to use

The WAN Tester III can be controlled from the front panel or from a local or remote terminal. It includes a 320 x 240 Color LCD display that shows selected mode, test and operating parameters. Parameters are selected by scrolling through values stored in the Tester.

WAN Tester III

Specifications

T-1
Framing: Framed or Unframed
Speed: 1,544,000 bps
Displays: Bit Errors, Bit Error Rate, RX Level Volts/dB, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Signalling Bits, Density Errs, Frame Errs, CRC Err, BPV Err, Slips, Round Trip Delay
LEDS: Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, D4, ESF, AMI, B8ZS and Yellow
Line 2: Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, D4, ESF, AMI, B8ZS and Yellow
Patterns: 2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, T-1 DALY, T-1 DALY UF, 55 Octet, 55 Octet UF, Alt, Mark, Space , Digimwatt, User 3 - 32, Round Trip Delay, DDS OCU Loop, DDS CSU Loop and DDS DSU Loop
Loops: Self-Test, ATT Loop U/D, ANSI Loop U/D, ATT Payload, ANSI Payload, Smart Jack 1 & 2 (Framed & Unframed) and V.54
Interfaces: Dual DS1 BiPolar, 110 Ohm, AMI/B8ZS Coding Physical: RJ48C & dual bantam

T-1 on T3
Framing: Framed or Unframed
Speed: 44,736,000 bps
Displays: Bit Errors, Bit Error Rate, T-3 RX Level, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, P-Bit Errs, C-Bit Errs, T3 & T2 Frame Errs, LCV Err, FEBE Err, Excessive 0s and LOS Secs
LEDS: Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, LCV, FEBE, Yellow, M13 and C-Bit
Line 2: Frame Lock, AIS (Blue), RLOS, LOF, LCV, FEBE, Yellow, M13 and C-Bit
Patterns: 2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1111, IDLE 1100, AIS 1010, 0000, 1 of 8 and User 3 - 32
Loops: Self-Test, T-1 CSU, T-3 Chan and V.54
Interfaces: Dual DS3 BiPolar, 75 Ohm Physical: Dual Mini WECo 560A

T-3 Unchannelized
Framing: Framed or Unframed
Speed: 44,736,000 bps
Displays: Bit Errors, Bit Error Rate, T-3 RX Level, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, P-Bit Errs, C-Bit Errs, T3 & T2 Frame Errs, LCV Err, FEBE Err, Excessive 0s and LOS Secs
LEDS: Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, LCV, FEBE, Yellow, M13 and C-Bit
Line 2: Frame Lock, AIS (Blue), RLOS, LOF, LCV, FEBE, Yellow, M13 and C-Bit
Patterns: 2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1111, IDLE 1100, AIS 1010, 0000, 1 of 8 and User 3 - 32
Loops: Self-Test and CSU
Interfaces: Dual DS3 BiPolar, 75 Ohm Physical: Dual Mini WECo 560A

E-1
Framing: Framed or Unframed
Speed: 2,048,000 bps
Displays: Bit Errors, Bit Error Rate, E-1 RX Level, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, CRC Errs, BPV Errs and Frame Errs
LEDS: Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Line 2: Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Patterns: 2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, Alt, Mark, Space, Digimwatt and User 3 - 32
Loops: Self-Test and V.54
Interfaces: Dual G.703/704, 75 & 120 Ohm, HDB3 Coding Physical: RJ48C & dual bantam

E-1 on T-3 (G.747)
Framing: Framed or Unframed
Speed: 44,736,000 bps
Displays: Bit Errors, Bit Error Rate, T-3 RX Level, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, CRC Errs, BPV Errs and Frame Errs
LEDS: Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Line 2: Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Patterns: 2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, Alt, Mark, Space, Digimwatt and User 3 - 32
Loops: Self-Test and V.54
Interfaces: Dual G.703/704, 75 & 120 Ohm, HDB3 Coding Physical: RJ48C & dual bantam

WAN Tester III

Specifications

E-1 on E-3

Framing:	Framed or Unframed
Speed:	34,368,000 bps
Displays:	Bit Errors, Bit Error Rate, E-3 RX Level, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, CRC Errs, BPV Errs and Frame Errs
LEDS:	Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA Line 2: Frame Lock, AIS (Blue), RLOS, CRC Err, BPV, DMFA and RRA
Patterns:	2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, Alt, Mark, Space, Digimwatt and User 3 - 32
Loops:	Self-Test and V.54
Interfaces:	Dual G.703/704, 75 & 120 Ohm, HDB3 Coding Physical: RJ48C & dual bantam

E-3 Unchannelized

Framing:	Framed or Unframed
Speed:	34,368,000 bps
Displays:	Bit Errors, Bit Error Rate, E-3 RX Level, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, LCVs, LOS Secs and Frame Errs
LEDS:	Line 1: Pattern Lock, Pattern Recovered, Frame Lock, AIS (Blue), RLOS, LOF, BPV, and RAI Line 2: Frame Lock, AIS (Blue), RLOS, LOF, BPV, and RAI
Patterns:	2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, Alt, Mark, Space and User 3 - 32
Loops:	Self-Test and LINE
Interfaces:	Dual G.703/751, 75 Ohm, HDB3 Coding Physical: Dual Mini WECo 560A

SYNC

Speeds:	1,200 to 50,000,000 bps
Displays:	Bit Errors, Bit Error Rate, Test Secs, Errored Secs, Severely Errored Secs, Degraded Mins, Available, Unavailable, RX Freq, TX Freq, Bits Received, RTS Time, Round Trip Delay
LEDS:	Pattern Lock, Pattern Recovered, Transmit Data, Receive Data, RTS (C), CTS, DSR, CD (I), DTR, TXC, RXC (S), and External TXC
Patterns:	2^9 (511), 2^11 (2047), 2^15, ITU 2^15, QRSS, 2^20, ITU 2^20, 2^23, ITU 2^23, 1 of 8, 3 of 24, Alt, Mark, Space and Round Trip Delay
Loops:	Self-Test and V.54
Interfaces:	V.35/DB25, RS530/DB25, RS422/DB25, RS232/DB25, X.21/DB15 and HSSI/50 pin

ASYNC

Speeds:	50 to 115,000 bps
Displays:	Character Errors, Characters Received, Total Test Seconds and Errored Seconds
LEDS:	Pattern Lock, Pattern Recovered, TXD, RXD, RTS, CTS, DSR, CD, and DTR
Patterns:	2^9 (511), 2^11 (2047), Binary, Fox Test, Mark and Space
Loops:	Self-Test
Interfaces:	V.35, RS530, RS422 and RS232 Physical: DB 25 pin Female
Mechanical:	The WAN Tester III measures 8.75" (22.2 cm) H x 7.5" (19.1 cm) W x 4" (10.2 cm) D and weighs 4.4 lbs (1.81 kg)

The WAN Tester III is supplied complete with all the interfaces pictured above.

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